

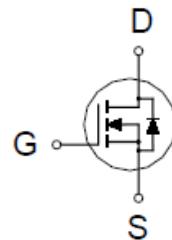
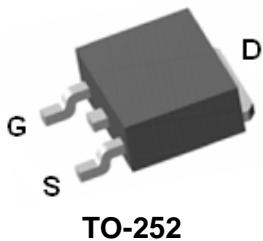


# P3004BD

## N-Channel Enhancement Mode MOSFET

### PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
40V	30mΩ @ $V_{GS} = 10V$	29A



100% Rg tested

### ABSOLUTE MAXIMUM RATINGS ( $T_A = 25^\circ C$ Unless Otherwise Noted)

100% UIS tested

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current $T_C = 25^\circ C$	$I_D$	29	A
		23	
Pulsed Drain Current <sup>1</sup>	$I_{DM}$	80	
Avalanche Current	$I_{AS}$	19	
Avalanche Energy	$E_{AS}$	19	mJ
Power Dissipation $T_C = 25^\circ C$	$P_D$	42	W
		27	
Operating Junction & Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

### THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{0JC}$	3	62.5	°C / W
Junction-to-Ambient	$R_{0JA}$			

<sup>1</sup>Pulse width limited by maximum junction temperature.



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### ELECTRICAL CHARACTERISTICS ( $T_J = 25^\circ\text{C}$ , Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNITS
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(\text{BR})\text{DSS}}$	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	40			V
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}} = V_{\text{GS}}, I_D = 250\mu\text{A}$	1.7	1.9	3.0	
Gate-Body Leakage	$I_{\text{GSS}}$	$V_{\text{DS}} = 0\text{V}, V_{\text{GS}} = \pm 20\text{V}$			$\pm 250$	nA
Zero Gate Voltage Drain Current	$I_{\text{DSS}}$	$V_{\text{DS}} = 32\text{V}, V_{\text{GS}} = 0\text{V}$			1	$\mu\text{A}$
		$V_{\text{DS}} = 30\text{V}, V_{\text{GS}} = 0\text{V}, T_J = 125^\circ\text{C}$			10	
On-State Drain Current <sup>1</sup>	$I_{\text{D}(\text{ON})}$	$V_{\text{DS}} = 10\text{V}, V_{\text{GS}} = 10\text{V}$	80			A
Drain-Source On-State Resistance <sup>1</sup>	$R_{\text{DS}(\text{ON})}$	$V_{\text{GS}} = 10\text{V}, I_D = 18\text{A}$		25	30	$\text{m}\Omega$
		$V_{\text{GS}} = 7\text{V}, I_D = 12\text{A}$		31	38	
Forward Transconductance <sup>1</sup>	$g_{\text{fs}}$	$V_{\text{DS}} = 10\text{V}, I_D = 10\text{A}$		25		S
<b>DYNAMIC</b>						
Input Capacitance	$C_{\text{iss}}$	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 20\text{V}, f = 1\text{MHz}$		479		pF
Output Capacitance	$C_{\text{oss}}$			117		
Reverse Transfer Capacitance	$C_{\text{rss}}$			76		
Gate Resistance	$R_g$	$V_{\text{GS}} = 0\text{V}, V_{\text{DS}} = 0\text{V}, f = 1\text{MHz}$		1.7		$\Omega$
Total Gate Charge <sup>2</sup>	$Q_g$	$V_{\text{DS}} = 20\text{V}, V_{\text{GS}} = 10\text{V}, I_D = 18\text{A}$		10		nC
Gate-Source Charge <sup>2</sup>	$Q_{\text{gs}}$			2.8		
Gate-Drain Charge <sup>2</sup>	$Q_{\text{gd}}$			3.3		
Turn-On Delay Time <sup>2</sup>	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = 20\text{V}, I_D \approx 6.7\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GEN}} = 6\Omega$		15		nS
Rise Time <sup>2</sup>	$t_r$			10		
Turn-Off Delay Time <sup>2</sup>	$t_{\text{d}(\text{off})}$			34		
Fall Time <sup>2</sup>	$t_f$			10		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_J = 25^\circ\text{C}</math>)</b>						
Continuous Current	$I_S$				29	A
Forward Voltage <sup>1</sup>	$V_{\text{SD}}$	$I_F = 18\text{A}, V_{\text{GS}} = 0\text{V}$			1.3	V
Reverse Recovery Time	$t_{\text{rr}}$	$I_F = 18\text{A}, dI_F/dt = 100\text{A}/\mu\text{s}$		38		nS
Reverse Recovery Charge	$Q_{\text{rr}}$			29		nC

<sup>1</sup>Pulse test : Pulse Width  $\leq 300\ \mu\text{sec}$ , Duty Cycle  $\leq 2\%$ .

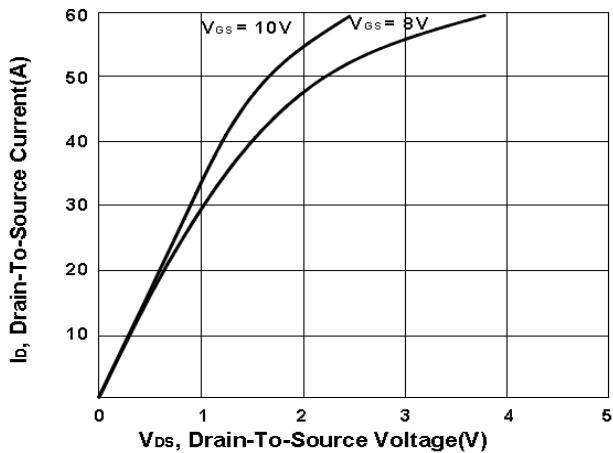
<sup>2</sup>Independent of operating temperature.



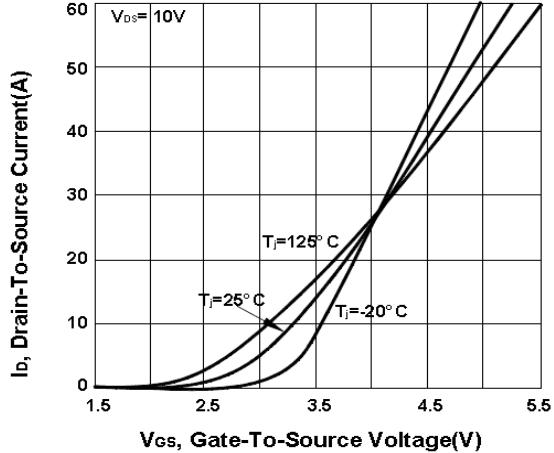
# P3004BD

## N-Channel Enhancement Mode MOSFET

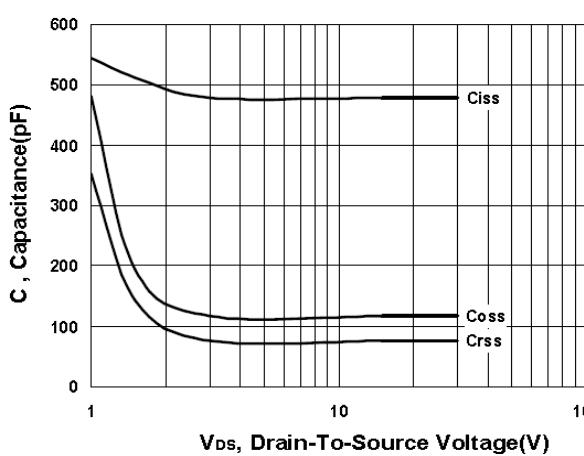
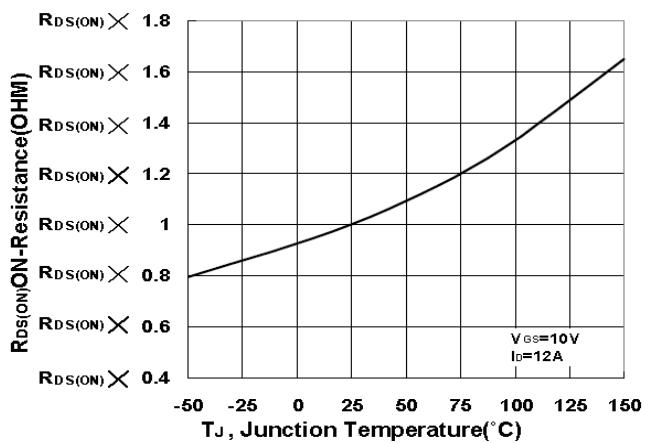
**Output Characteristics**



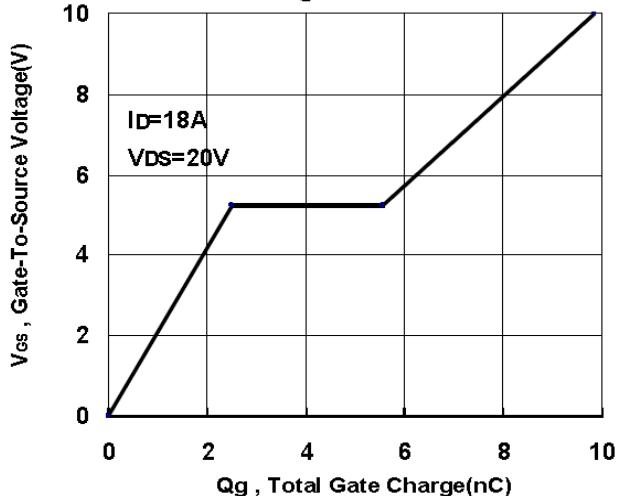
**Transfer Characteristics**



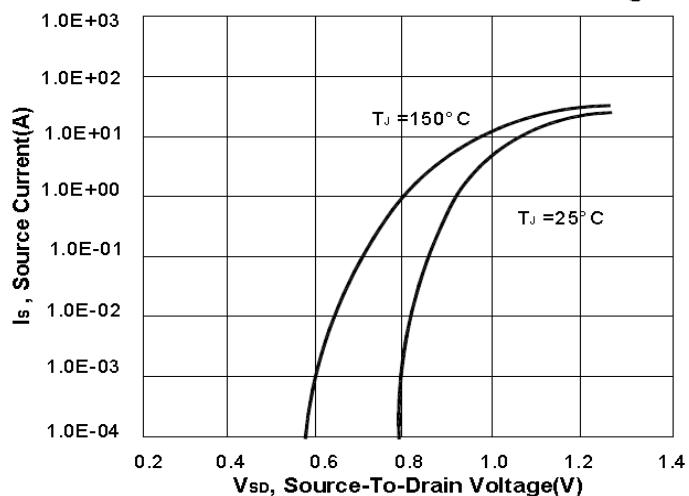
**On-Resistance VS Temperature**



**Gate charge Characteristics**



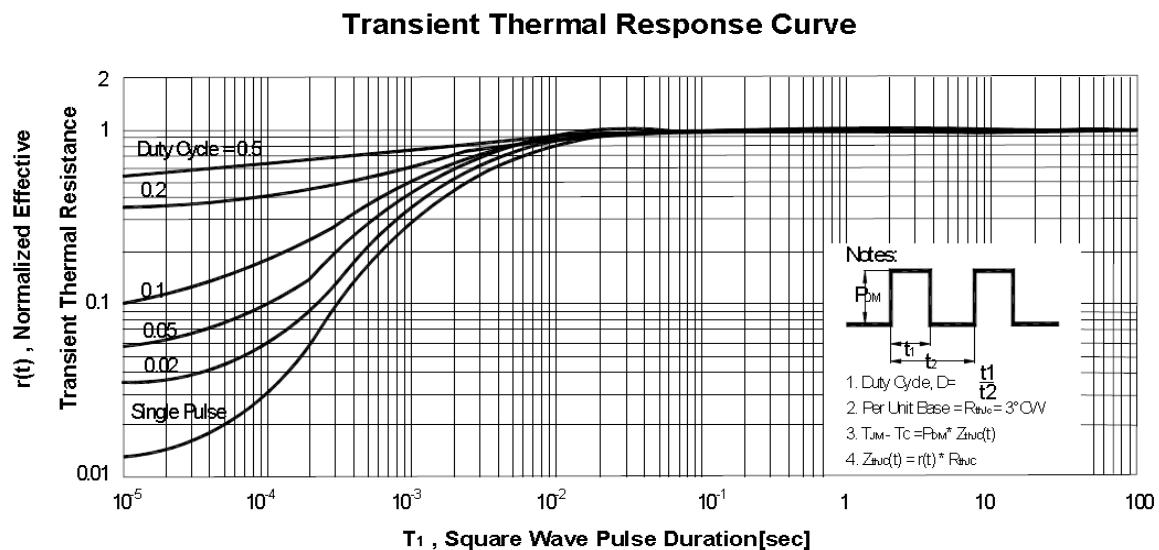
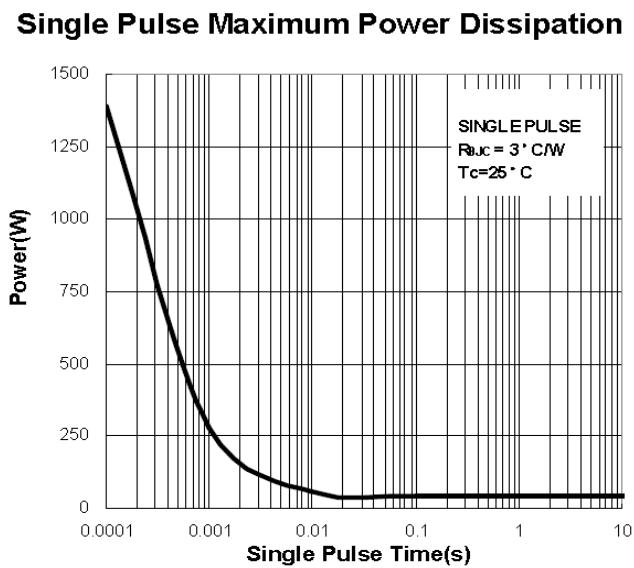
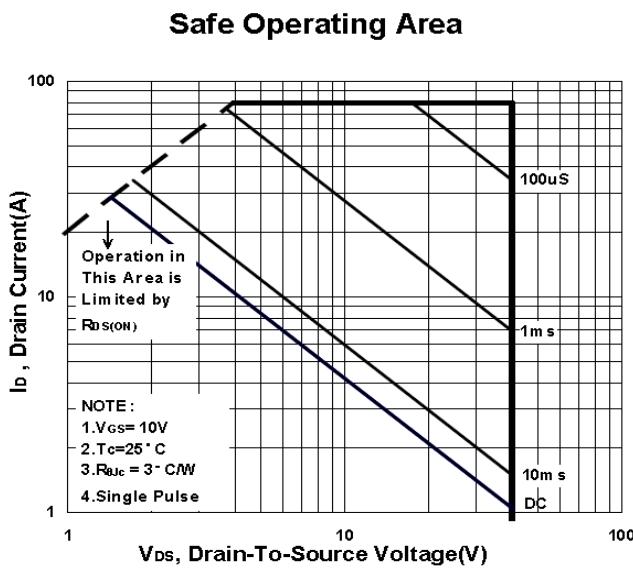
**Source-Drain Diode Forward Voltage**





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## N-Channel Enhancement Mode MOSFET

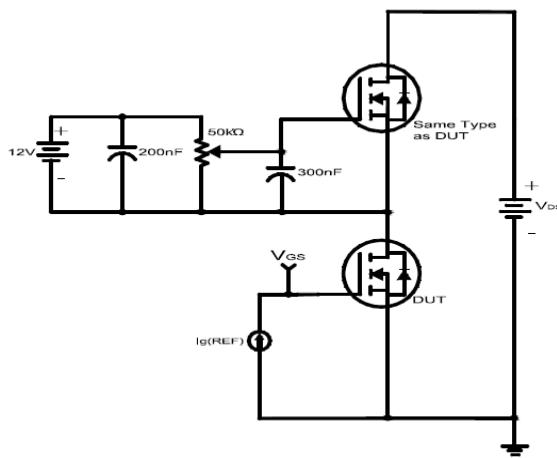




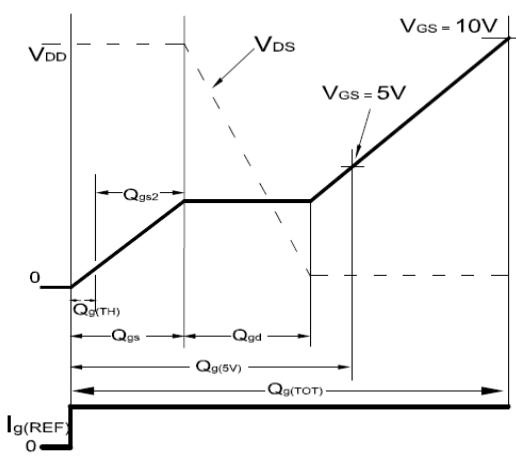
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## N-Channel Enhancement Mode MOSFET

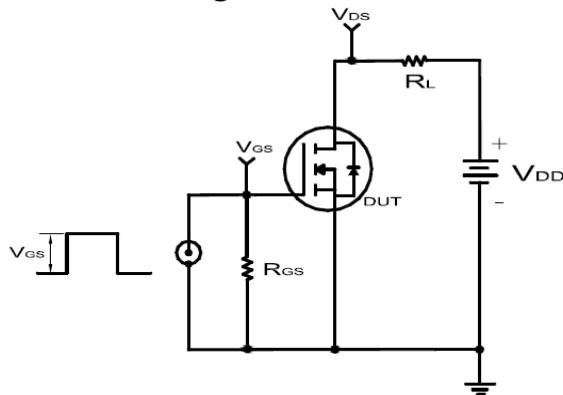
**Figure 1**  
Gate Charge Test Circuit



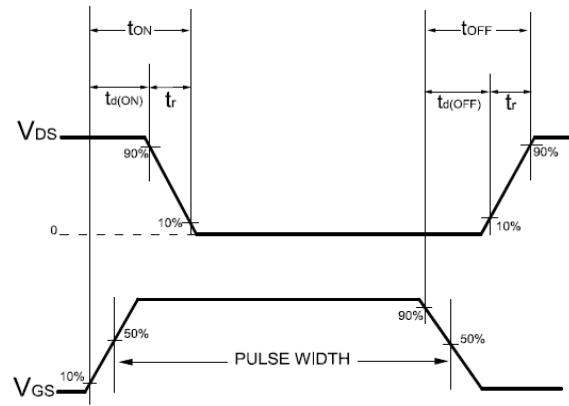
**Figure 2**  
Gate Charge Waveforms



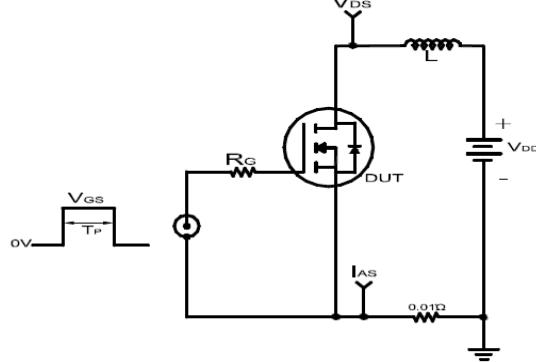
**Figure 3**  
Switching Time Test Circuit



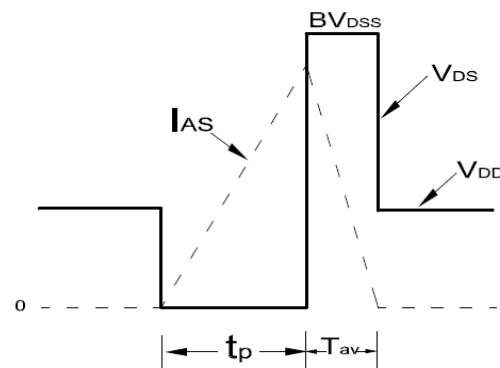
**Figure 4**  
Switching Time Waveforms



**Figure 5**  
Unclamped Energy Test Circuit



Unclamped Energy Waveforms

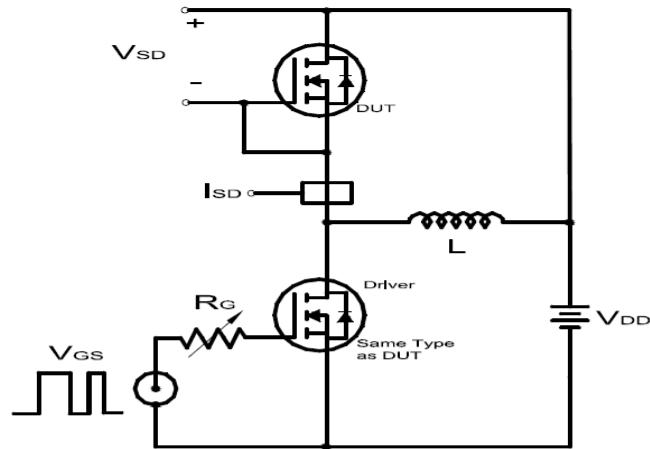




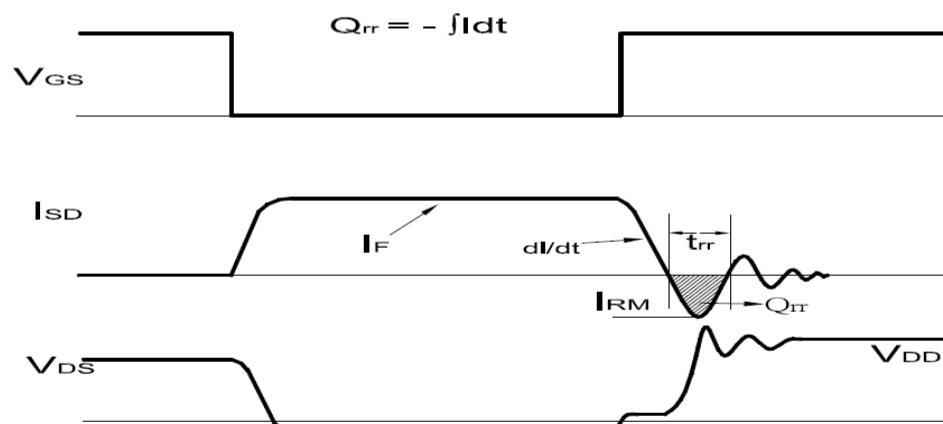
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### N-Channel Enhancement Mode MOSFET

**Figure 7**  
**Diode Recovery Test Circuit**



**Figure 8**  
**Diode Recovery Test Waveforms**





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### N-Channel Enhancement Mode MOSFET

#### Package Dimension

#### TO-252 (DPAK) MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	8.9	10	10.41	J	4.8		5.64
B	2.1	2.2	2.5	K	0.15		1.49
C	0.4	0.5	0.61	L	0.4	0.76	0.91
D	0.82	1.2	1.5	M	4.2	4.58	5
E	0.35	0.5	0.65	S	4.57	5.1	5.52
F	0		0.2	T	3.81	4.75	5.24
G	5.3	6.1	6.3	U	1.4		1.78
H	0.5		1.7	V	0.55	1.25	1.7
I	6.3	6.5	6.8				

